

<b>STUDY MODULE DESCRIPTION FORM</b>		
Name of the module/subject <b>Quantum Metrology</b>		Code <b>1010832121010832686</b>
Field of study <b>Electronics and Telecommunications</b>	Profile of study (general academic, practical) <b>general academic</b>	Year /Semester <b>1 / 2</b>
Elective path/specialty <b>Telecommunication Systems</b>	Subject offered in: <b>Polish</b>	Course (compulsory, elective) <b>elective</b>
Cycle of study: <b>Second-cycle studies</b>	Form of study (full-time, part-time) <b>full-time</b>	
No. of hours Lecture: <b>2</b> Classes: <b>-</b> Laboratory: <b>2</b> Project/seminars: <b>-</b>		No. of credits <b>5</b>
Status of the course in the study program (Basic, major, other) <b>other</b>		(university-wide, from another field) <b>from field</b>
Education areas and fields of science and art <b>technical sciences</b> <b>Technical sciences</b>		ECTS distribution (number and %) <b>5 100%</b> <b>5 100%</b>
<b>Responsible for subject / lecturer:</b>  prof. dr hab. inż. Waldemar Nawrocki email: nawrocki@et.put.poznan.pl tel. 61665 3888 Electronics and Telecommunications Polanka 3		
<b>Prerequisites in terms of knowledge, skills and social competencies:</b>		
<b>1</b>	<b>Knowledge</b>	1. Student has a systematic knowledge of physics, in particular of solid-state physics . (K1_W01) 2. Student has a basic knowledge of electronics and metrology (K1_W02) (K1_W05)
<b>2</b>	<b>Skills</b>	1. Is able to extract information from Polish or English language literature, databases and other sources. Is able to synthesize gathered information, draw conclusions, and justify opinions. (K1_U01) 2. Is capable of studying autonomously. (K1_U05) 3. Demonstrates the ability to solve basic problems in physics. (K1_U08)
<b>3</b>	<b>Social competencies</b>	1. Is aware of the limitations of his/her current knowledge and skills; is committed to further self-study. (K1_K01) 2. Is able to participate in collaborative projects. (K1_K02)
<b>Assumptions and objectives of the course:</b> -To present of the basic definitions and concepts of metrology, measurements in physics and measurement equipment. To introduce students to the analysis and presentation of data and the determination of errors and measurement uncertainty. Practical carrying out laboratory experiments involving the preparation and execution of measurements.		
<b>Study outcomes and reference to the educational results for a field of study</b>		
<b>Knowledge:</b>		
1. Has a systematic knowledge, together with necessary mathematical background, of the fundamentals of metrology, which is necessary to measure the signal properties and the parameters of electronic and telecommunication systems components. Has knowledge of measurement methods, measurement equipment. - [K2_W02] 2. Has a knowledge of devices and systems exploitation. - [K2_W06] 3. Has a knowledge of classical and quantum standards of electrical resistance - [K2_W08] 4. Has a knowledge of sensitive electronic amplifiers - [K2_W10]		
<b>Skills:</b>		

<p>1. Is able to extract information from Polish or English language literature, databases and other sources. Is able to synthesize gathered information, draw conclusions, and justify opinions. - [K2_U01]</p> <p>2. Is able to prepare a well-documented study, in English or in Polish, on problems related to electronics and telecommunication. - [K2_U03]</p> <p>3. Is capable of studying autonomously. - [K2_U05]</p> <p>4. Is able to measure typical parameters of signals, systems and devices, in particular those used in telecommunication. Is able to choose appropriate methods to measure given electrical quantities and parameters of signals and devices. Is able to plan and perform measurements and analyze the results. - [K2_U07]</p> <p>5. Is able to design low noise amplifiers - [K2_U17]</p>
<p><b>Social competencies:</b></p> <p>1. Demonstrates responsibility and professionalism in solving technical problems. - [K2_K02]</p> <p>2. Demonstrates responsibility for standards of units in technology and sciences. - [K2_K03]</p> <p>3. Is aware of the main challenges facing metrology and systems of units in the 21st century. - [K2_K04]</p>

<b>Assessment methods of study outcomes</b>	
<p>-Lectures passing based on written test from content of the lectures.</p> <p>-Tests in laboratory.</p> <p>-Reports from laboratory experiments.</p>	
<b>Course description</b>	
<ul style="list-style-type: none"> <li>- Basic definitions and terms of metrology, in particular of quantum metrology.</li> <li>- Systems of units: history, standards of units, system of units now (SI system) and in the future - proposals.</li> <li>- Quantum system of units</li> <li>- Quantum metrological triangle and quantum metrological pyramid.</li> <li>- Basic terms in quantum metrology, Heisengerg`'s uncertainty principle, quantum noise, energy resolution.</li> <li>- Superconductivity. Josephson effect and its applications in metrology (voltage standards</li> <li>- Zjawisko Josephsona.</li> <li>- Direct current voltage standards. Setup of voltage standards in Warsaw.</li> <li>- SQUID detectors and their applications.</li> <li>- Classical and quantum Hall effect. Electrical resistance standard using quantum Hall effect.</li> <li>- Quantization of electrical conductance in nanostructures.</li> <li>- Single electron tunneling and a direct current standard.</li> <li>- Scanning probe microscopy for nanoscience and nano technology.</li> <li>- Frequency standards and atomic clocks. International Time Scale.</li> <li>- Optical interferometry for length standards.</li> <li>- Quantum standards of a mass.</li> <li>- Scale of temperature based on the Boltzmann constant.</li> <li>- Low noise preamplifiers.</li> <li>- Some problems of cryoelectronics.</li> </ul>	
<p><b>Basic bibliography:</b></p> <p>1. Wstęp do metrologii kwantowej, Nawrocki W., Wydawnictwo PP, Poznań 2007</p> <p>2. Technika pomiarowa, Tumański S., WNT, Warszawa 2007</p> <p>3. Komputerowe systemy pomiarowe. Ćwiczenia laboratoryjne, Wydawnictwo PP, Poznań 2007</p>	
<p><b>Additional bibliography:</b></p> <p>1. Systemy mikroskopii bliskich oddziaływań w badaniach mikro- i nanostruktur, Gotszalk T.P., Oficyna Wyd. Politechniki Wrocławskiej, Wrocław 2004</p> <p>2. Wzorcowanie aparatury pomiarowej, Piotrowski J. , Kostyrko K., Wydawnictwo Naukowe PWN, Warszawa 2012</p> <p>3. Practical Data Acquisition for Instrumentation and Control Systems, Park J. Mackey S., Elsevier, 2003</p>	
<b>Result of average student's workload</b>	
Activity	Time (working hours)
1. Participation in lectures and lab exercises.	62
2. Preparation for lab exercises.	25
3. Preparing lab reports.	19
4. Preparation to the test.	14

<b>Student's workload</b>		
<b>Source of workload</b>	<b>hours</b>	<b>ECTS</b>
Total workload	125	5
Contact hours	65	2
Practical activities	70	2